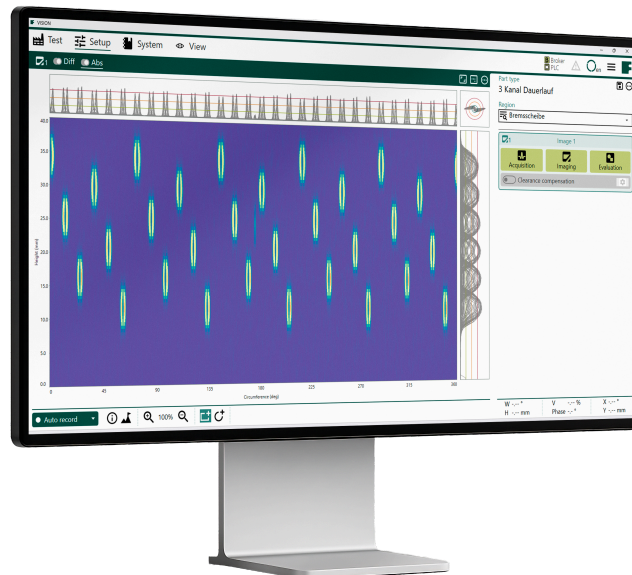




STATOVISION TCL

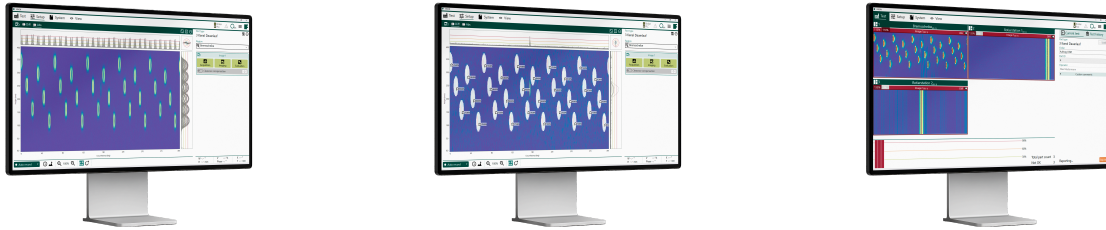
Software for Surface Quality Visualization



STATOVISION TCL

STATOVISION TCL

Software for Surface Quality Visualization



Innovative C-Scan Analysis of Eddy Current Data.

In combination with the eddy current testing instruments of the TCL product family, STATOVISION TCL displays inspection signals in a clear C-scan. This creates a precise representation of the component surface and enables highly accurate localization of surface defects.

Typical applications include crack detection and grinding burn testing on brake discs, camshafts, output shafts, sleeves, rolls, and complex components.

Up to four TCL test instruments can be integrated simultaneously – ideal for multi-channel applications, higher inspection speeds, or the parallel inspection of multiple test tracks and components.

As the evolution of the proven STATOVISION CM software, STATOVISION TCL centralizes all inspection settings in a single interface. This simplifies commissioning, parameterization, and day-to-day operation while ensuring reproducible inspection conditions.

Integrated pattern recognition identifies recurring interfering geometries such as holes, grooves, chamfers, or surface structures and selectively masks them out. This makes relevant defect indications clearly visible and enables reliable evaluation.

Comprehensive documentation of the inspection process supports quality assurance and ensures full traceability of every inspected component.

STATOVISION TCL is used as a complete solution with the specially designed STATOVISION Controller and can be flexibly connected to external monitors.

At the same time, STATOVISION TCL provides the foundation for future AI-supported applications. Surface images generated from eddy current data can be analyzed using customer-specific AI models – for example, to automatically recognize similar defect patterns, intelligently suppress interfering geometries, or integrate customized evaluation algorithms.

YOUR ADVANTAGES AT A GLANCE

High-resolution visualization: Detailed C-scans for intuitive evaluation of eddy current signals

Parallel multi-channel testing: Integration of up to 4 TCLs for higher inspection speeds and multi-track applications

Centralized configuration: Manage all system settings conveniently within a single software environment

Contour suppression: Selectively mask holes, grooves, and other interfering geometries

Complete traceability: Seamless documentation through storage of relevant inspection data

Integrated process monitoring: Continuous monitoring for early intervention in production processes

Advanced signal filtering: Improved signal quality for reliable defect detection

Clearance compensation: Directly during inspection or afterwards in post-processing

AI-ready architecture: Foundation for future AI-supported analysis and automation solutions

TECHNICAL INFORMATION

INSPECTION PARAMETERS	
FREQUENCY RANGE:	4 Hz to 20 MHz
FIELD CURRENT:	Max. 600 mA
TRIGGER:	External
RESOLUTION:	24-bit ADC
DATA RATE:	Max. 100 kHz
TCL	
DIMENSIONS & WEIGHT:	— 176 × 109 × 35 mm — approx. 0.5 kg
POWER SUPPLY:	24 V, 400 mA (power supply optional)
PROTECTION CLASS:	IP40
PERMISSIBLE AMBIENT TEMPERATURE:	+5 °C to +40 °C
PERMISSIBLE RELATIVE HUMIDITY:	8% to 80% (non-condensing)
CONTROLLER	
DIMENSIONS & WEIGHT:	240 × 225 × 90 mm; approx. 3.6 kg
POWER SUPPLY:	8–35 VDC input, 65 W (power supply optional)
OPERATING SYSTEM:	Windows
MONITOR INTERFACES:	VGA, DVI, DP
PERMISSIBLE AMBIENT TEMPERATURE:	-25 °C to +50 °C
PERMISSIBLE RELATIVE HUMIDITY:	10% to 90% (non-condensing)



foerstergroup.com



The FOERSTER Group is represented by subsidiaries and representatives in over 60 countries worldwide. You can find a complete overview on our website.

Headquarters

Institut Dr. Foerster GmbH & Co. KG

In Laisen 70
72766 Reutlingen
Germany

+49 7121 140 0
info@foerstergroup.com

© Copyright 2026 – Copyright notice: All contents of this work, in particular texts, photographs and graphics, are protected by copyright. Unless explicitly stated otherwise, the copyright lies with Institut Dr. Foerster GmbH & Co. KG. Please contact us if you wish to use any part of this work.

Generated: 2026-08-25 22:33:49